ITC 2008 Most Significant Paper Award

Starting this year, the ITC Steering Committee established the Most Significant Paper Award to recognize authors of a paper published 10 years ago at ITC that was outstanding in:

- **Impact and Significance** – The paper was highly significant at the time of its publication. It had a big impact on major area of test research, methodology, applications, and test technology.

- **Relevance** – The paper is still extremely relevant today to research, development and advanced industrial practice.

- **Historical Interest** – The paper was the first or early report on a new concept, standard, or idea.

For the 2008 ITC Most Significant Paper Award, the award committee has selected the following paper published at ITC 1998:

**A Structured and Scalable Mechanism for Test Access to Embedded Reusable Cores**  
E. Marinissen, R. Arendsen, G. Bos, H. Dingemanse, M. Lousberg, C. Wouters, Philips

International Test Conference congratulates the authors of this paper for their achievements, and long lasting impact of their work.

The International Test Conference congratulates the authors of these papers for their achievements and for the outstanding quality of their work.

The ITC 2008 Most Significant Paper Award Committee:

Rob Aitken, ARM
Anthony Ambler, The University of Texas at Austin
Ken Butler, Texas Instruments
Scott Davidson, Sun Microsystems
Janusz Rajski, Mentor Graphics